

Supporting Information

Modulating Polymer Ultrathin Film Crystalline Fraction and Orientation with Nanoscale Curvature

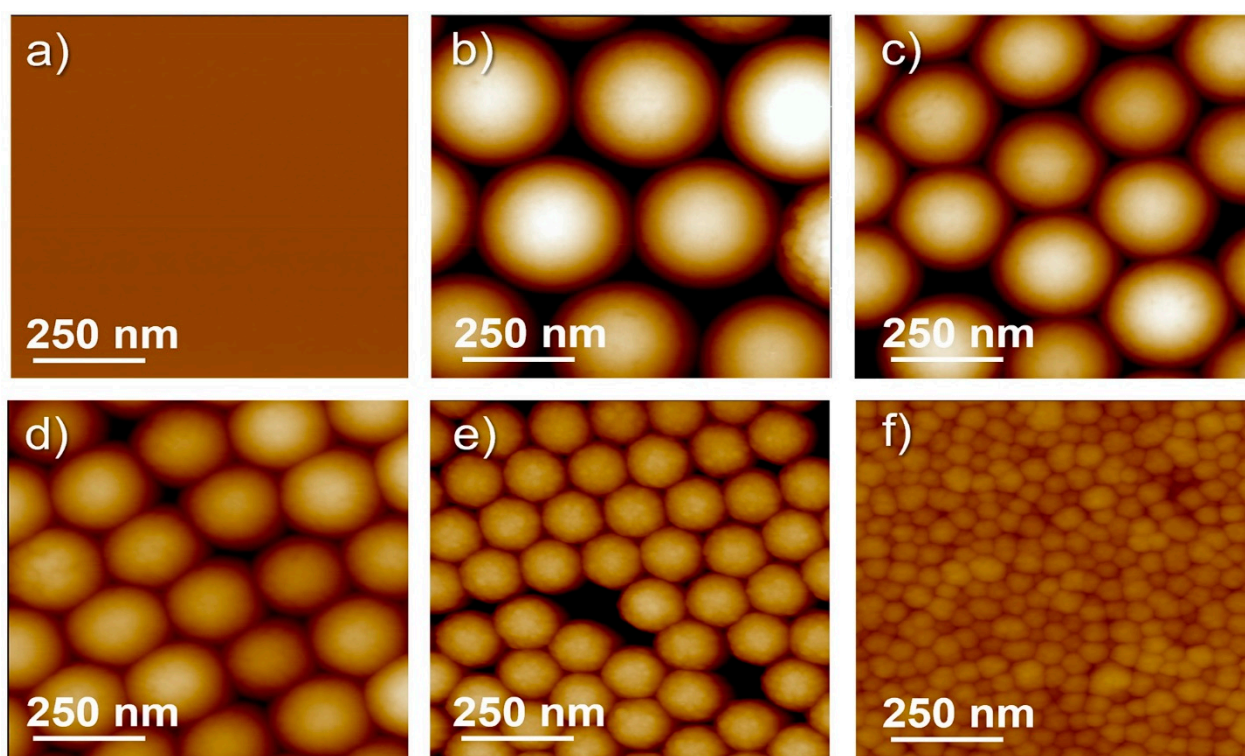


Figure S1. $1 \times 1 \mu\text{m}^2$ AFM height images (Z scale 150nm) of bare flat substrate (a) and of bare structured substrates with curvature of 0.00492 nm⁻¹ (b), 0.00658 nm⁻¹ (c), 0.00851 nm⁻¹ (d), 0.0140 nm⁻¹ (e) and 0.0400 nm⁻¹ (f).

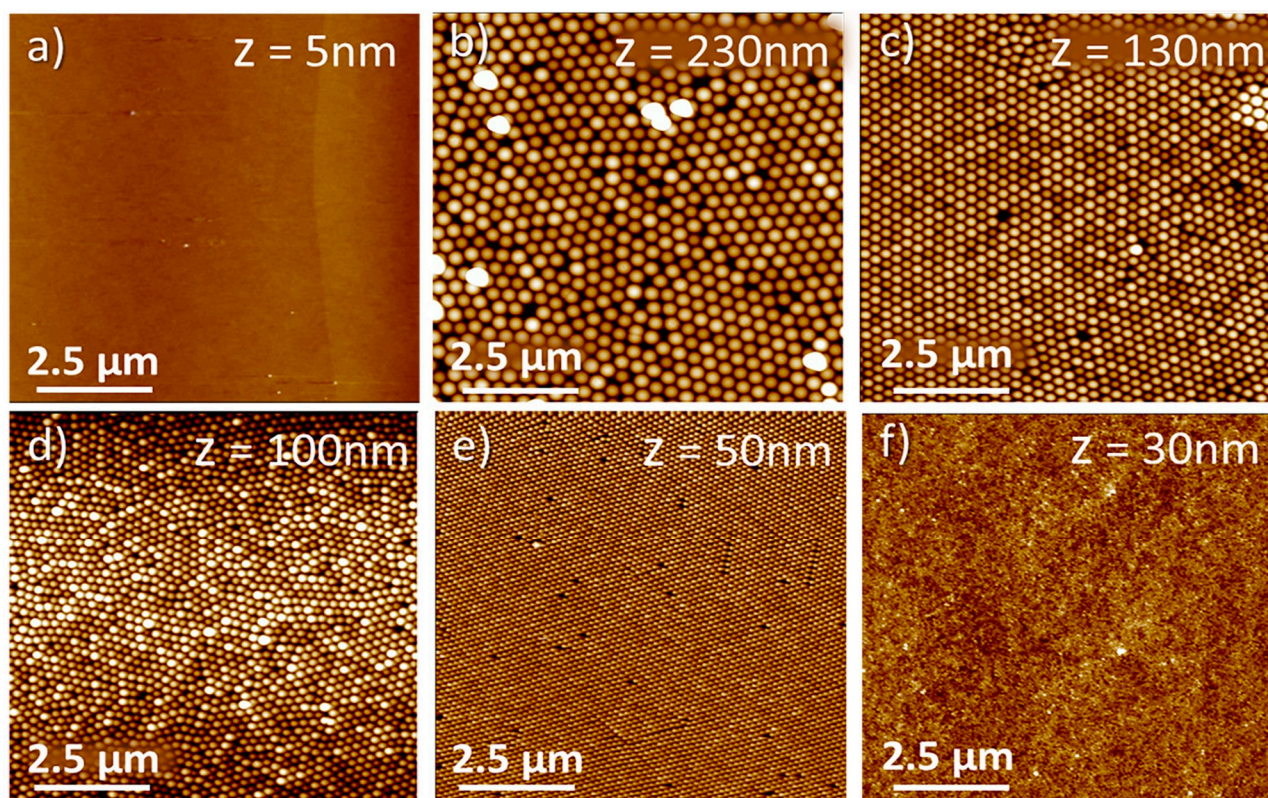


Figure S2. $10 \times 10\text{ }\mu\text{m}^2$ AFM height images of bare flat substrate (a) and of bare substrates having different curvature: 0.00492 nm^{-1} (b), 0.00658 nm^{-1} (c), 0.00851 nm^{-1} (d), 0.0140 nm^{-1} (e) and 0.0400 nm^{-1} (f).